Product Description

DELIVERY TERM IS WITHIN 6 MONTHS!

High Resolution High Resonant Frequency AFM Cantilevers HA_HR series are designed for Semicontact (Intermittent), Noncontact applications. Each probe has 2 rectangular cantilevers.Typical Resonant Frequency 380kHz / 230kHz (dispersion ±10%), Typical Force Constant 34N/m / 17N/m (dispersion ±20%). Cantilever has Au reflective side coating to increase laser signal. Probes are also available with no coating as well as with conductive tip coating.

Probes are packed in boxes with 15 and 50 pieces. Amount discount is included in the package price.

High Accuracy composite ETALON probes combine the main features allowing to obtain high quality AFM images:

- Sharp tip - curvature radius < 10 nm.
- Resonance frequency, specified with high accuracy - ±10% within a wafer.
- Special chip geometry with vertical sidewalls for convenient operating.
- High aspect ratio tip.
- Enhanced back-side reflection of the cantilever.

General Features

Material	Polysilicon cantilever, silicon tip
Chip size	3.6x1.6x0.4mm
Reflective side coating	Au
Tip coating	No
Tip curvature radius	< 10nm
Available tip coatings	Pt, Au, W2C

Special Features

Cantilever series	Cantilever	Cantilever length, L±2μm	Cantilever width, W±3μm	Cantilever thickness, T±0.15μm	Resonant frequency, kHz			Force constant, N/m		
					min	typical	max	min	typical	max
HA_HR	A	93	34	3.0	342	380	418	27	34	41
	B	123	34	3.0	207	230	253	13	17	21